OIPE JC53 JAN 23 2004 PATENT & TRADEMARK

FIG. 1

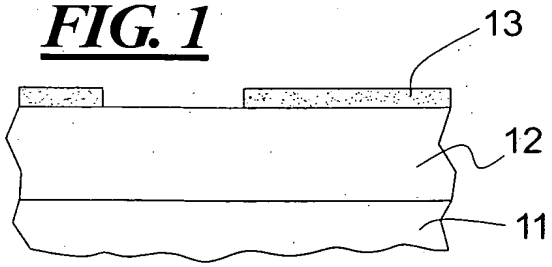

FIG. 2

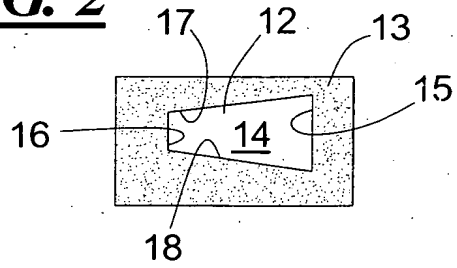

FIG. 3

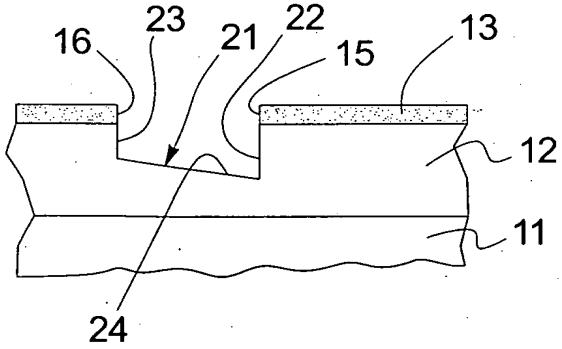

FIG. 4

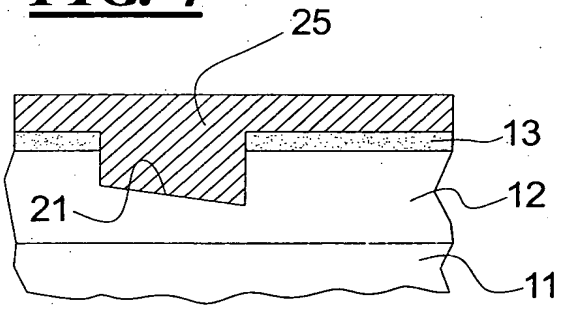

FIG. 5

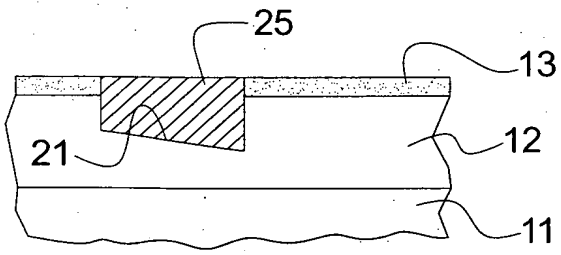

FIG. 6A

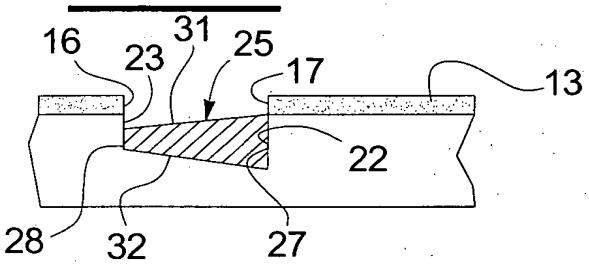

FIG. 6B

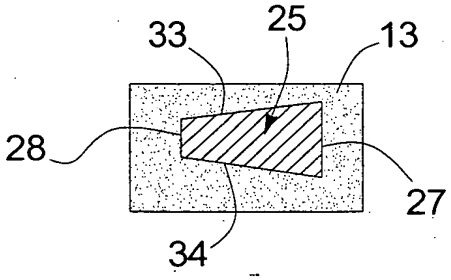

FIG. 6C

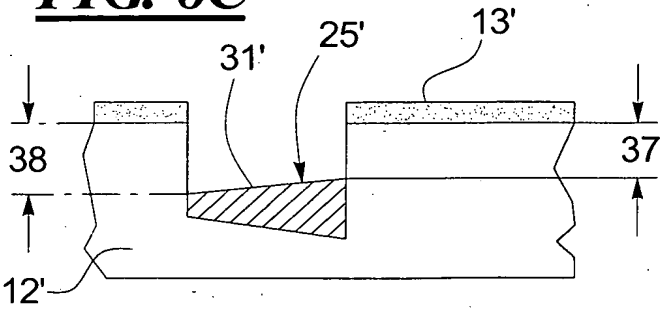

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FIG. 7

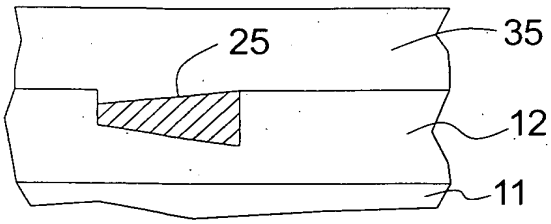


FIG. 8

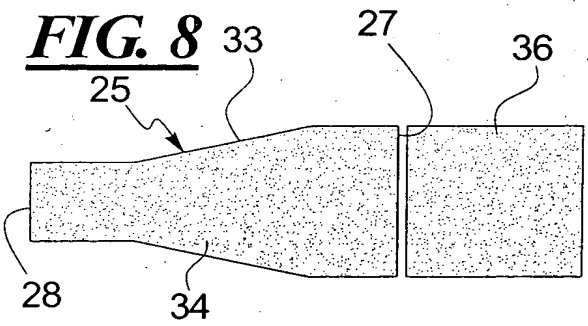


FIG. 9

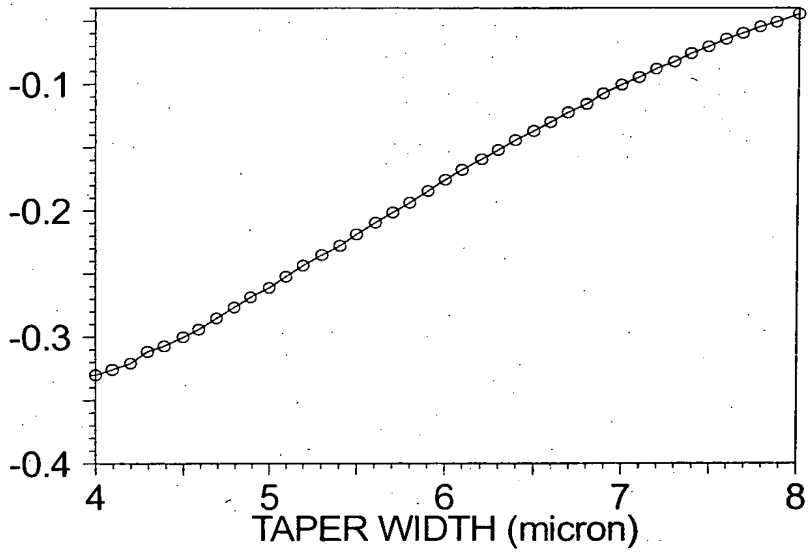


FIG. 10

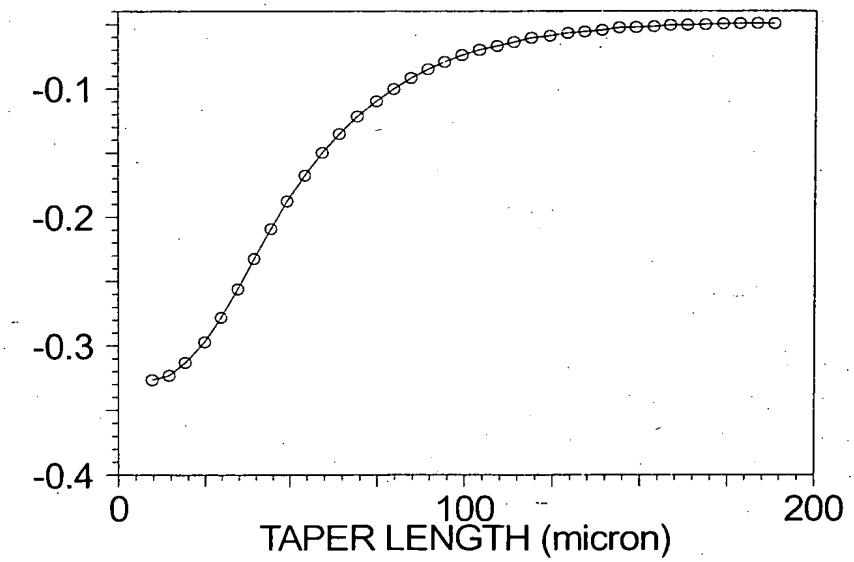
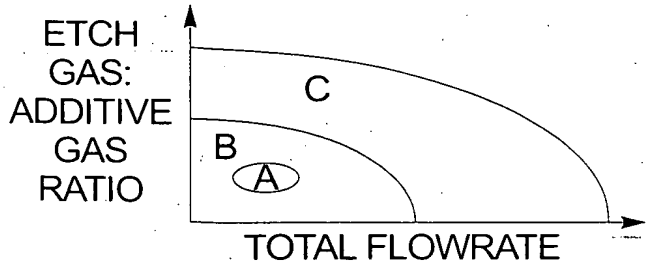


FIG. 11



ETCH RATE OF SMALL FEATURE:
ETCH RATE OF LARGE FEATURE
A≈1-2 (REVERSE RIE LAG)
B≈1 (NO RIE LAG)
C≈0.5 (RIE LAG)